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PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Inventors: Allan Rosencwaig, et al.

Application No.: 09/629,407

Filed: August 1, 2000

For: MEASUREMENT OF THIN FILMS  
AND BARRIER LAYERS ON  
PATTERNED WAFERS WITH X-RAY  
REFLECTOMETRY

Confirmation No.: 6057

Group Art Unit: 2882

Examiner: Hoon K. Song

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